

PSI Center for
Photon Science

Optimizing Charge Sharing Simulation

for Deep Learning Enhanced Spatial Resolution of the MÖNCH Detector

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Outline



Introduction

Optimizing simulation

Validation

Discussion and summary

Introduction: Deep Learning Enhanced Spatial Resolution of the MÖNCH Detector

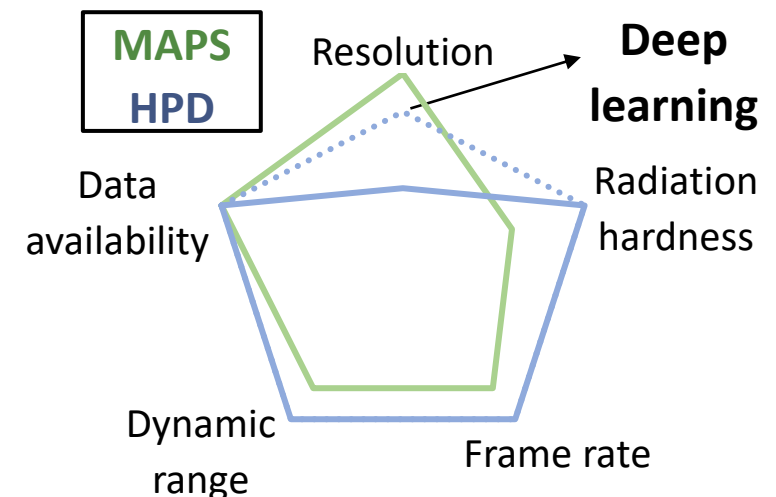
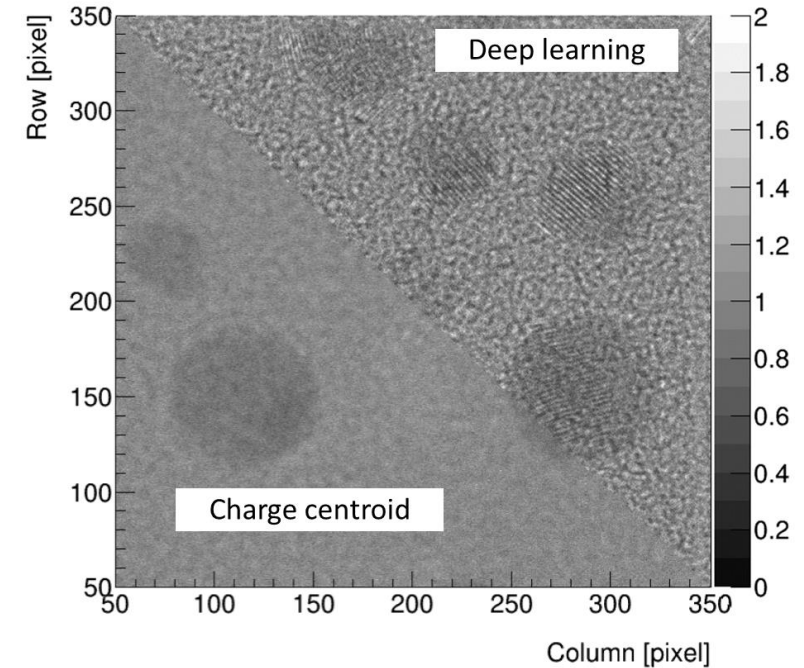
MÖNCH key specifications

- 25 μm hybrid pixel detector with silicon sensor
- Charge integrating mode, 6 kHz frame rate

Previous study

- Use deep learning to reconstruct incident position of each 200 keV electron
 - To learn the nature of **electron multiple scattering** and **charge diffusion**
- Spatial resolution improved by a **factor of three** [1]
 - Experiment-based training: **0.60 pixel**
 - Simulation-based training: **0.70 pixel**
- Potential in electron microscopy applications

[1] X. Xie *et al* 2024 *JINST* **19** C01020



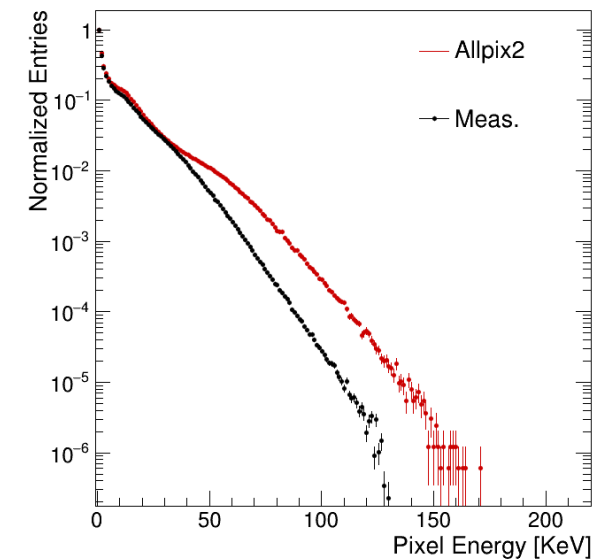
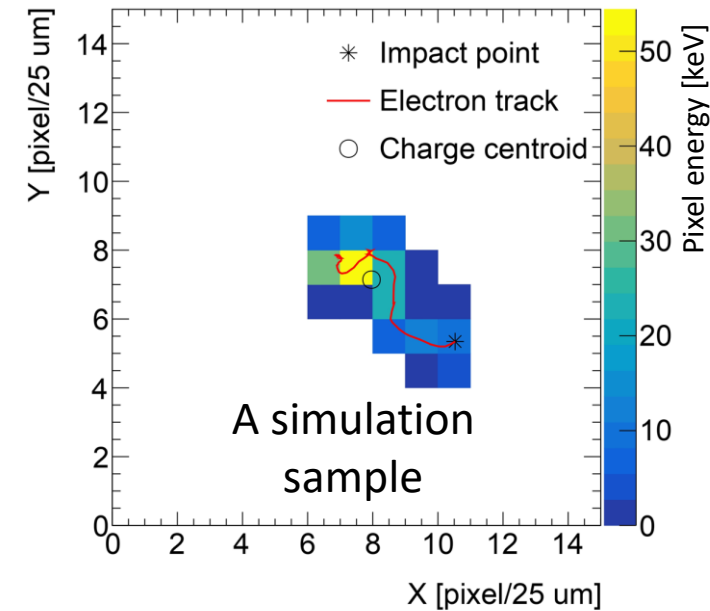
Introduction: Discrepancy between Simulation and Measurements

Simulation samples still matter

- Availability and flexibility
 - No special experimental setup required
 - Different electron energies
 - Different detector designs
- More information
 - 3D electron trajectory in silicon sensor

Single Pixel Energy Spectrum for electrons

- Pixels selected from 200 keV electron clusters
- Simulation tool: Allpix2
 - *Projection propagation module* to simulate drift and diffusion of charge carriers



Introduction: Discrepancy in Single Pixel Energy Spectrum for X-rays

Further investigation using X-ray

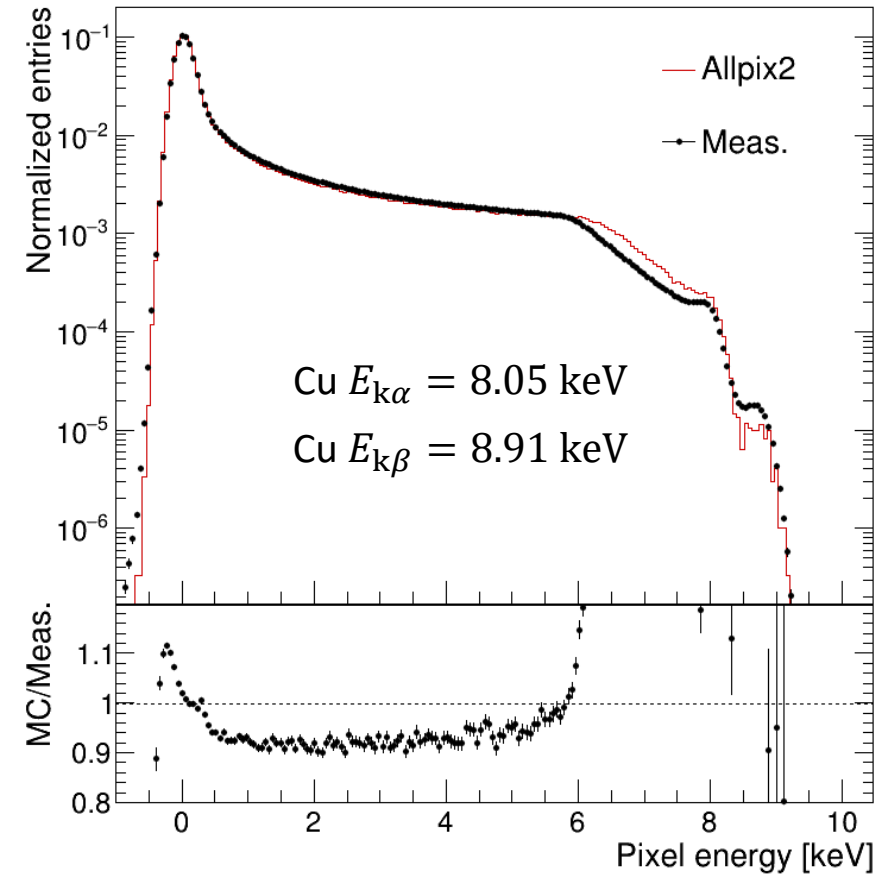
- Simplest case without particle trajectory
- Energy deposited in a point-like region

Pixels selected from 3x3-pixel clusters

- Same Allpix2 simulation setup
- Measured using X-ray tube

Discrepancy remains

- Simulation overestimates pixel energy
- Chare sharing is underestimated
- Discrepancy related to deposited energy



Reason: absence of repulsion simulation

Continuity equation for charge carriers in silicon: $\frac{\partial p}{\partial t} = D\Delta p - \underbrace{\nabla \cdot (p\mu\vec{E})}_{\text{repulsion}}$

diffusion

- $p(r, t)$: charge carrier density
- $D = \mu \frac{kT}{q}$, Einstein equation
- Drift treated independently

By neglecting the charge repulsion

- Simplified to be $\frac{\partial p}{\partial t} = D\Delta p$
- 1D solution $p(x, t) \sim N(0, \sqrt{2Dt})$
- Implemented in current allpix2 propagation modules

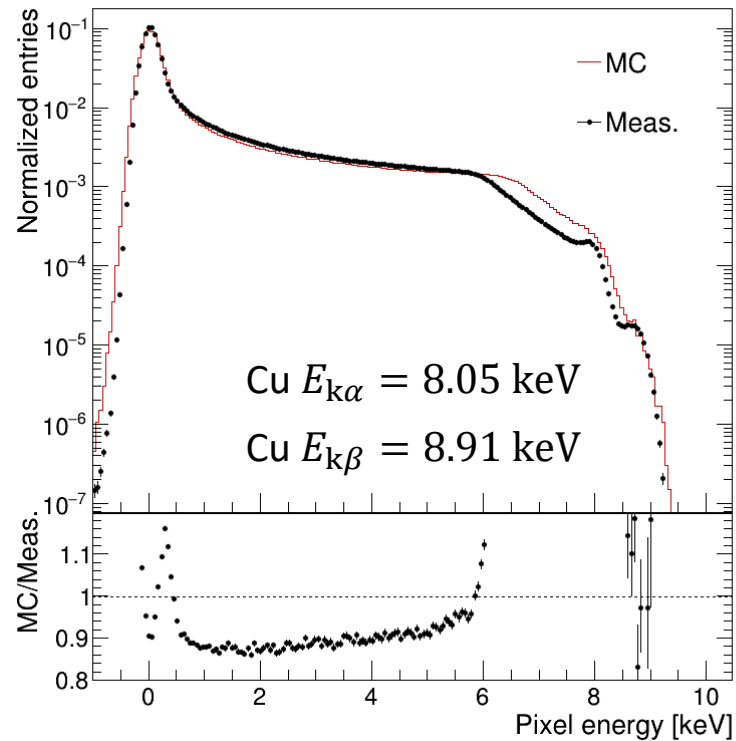
But not the case for HPD for X-ray/electron detection

- Deposited energy up to several dozen keV
- Charge repulsion is not negligible

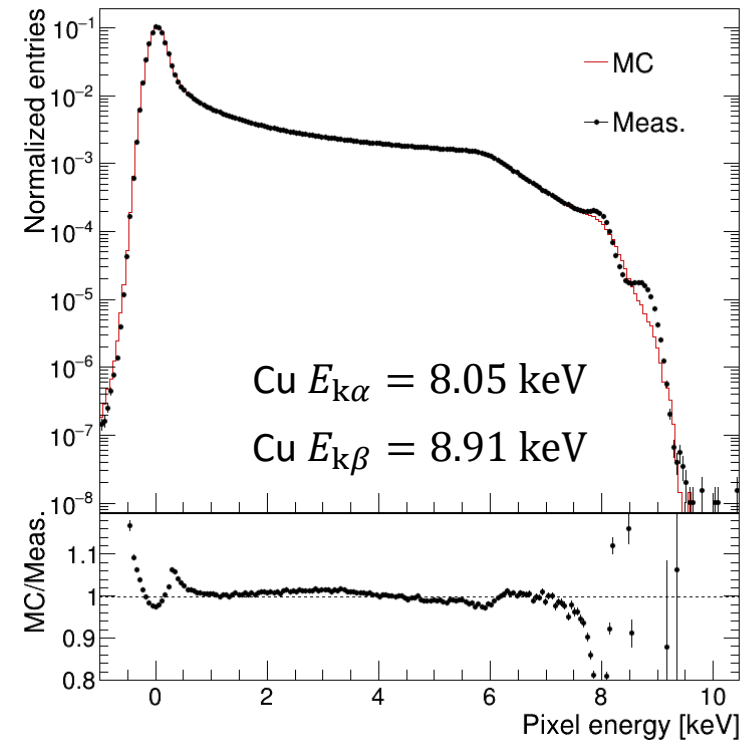
Introduction: Results of the Optimized Simulation

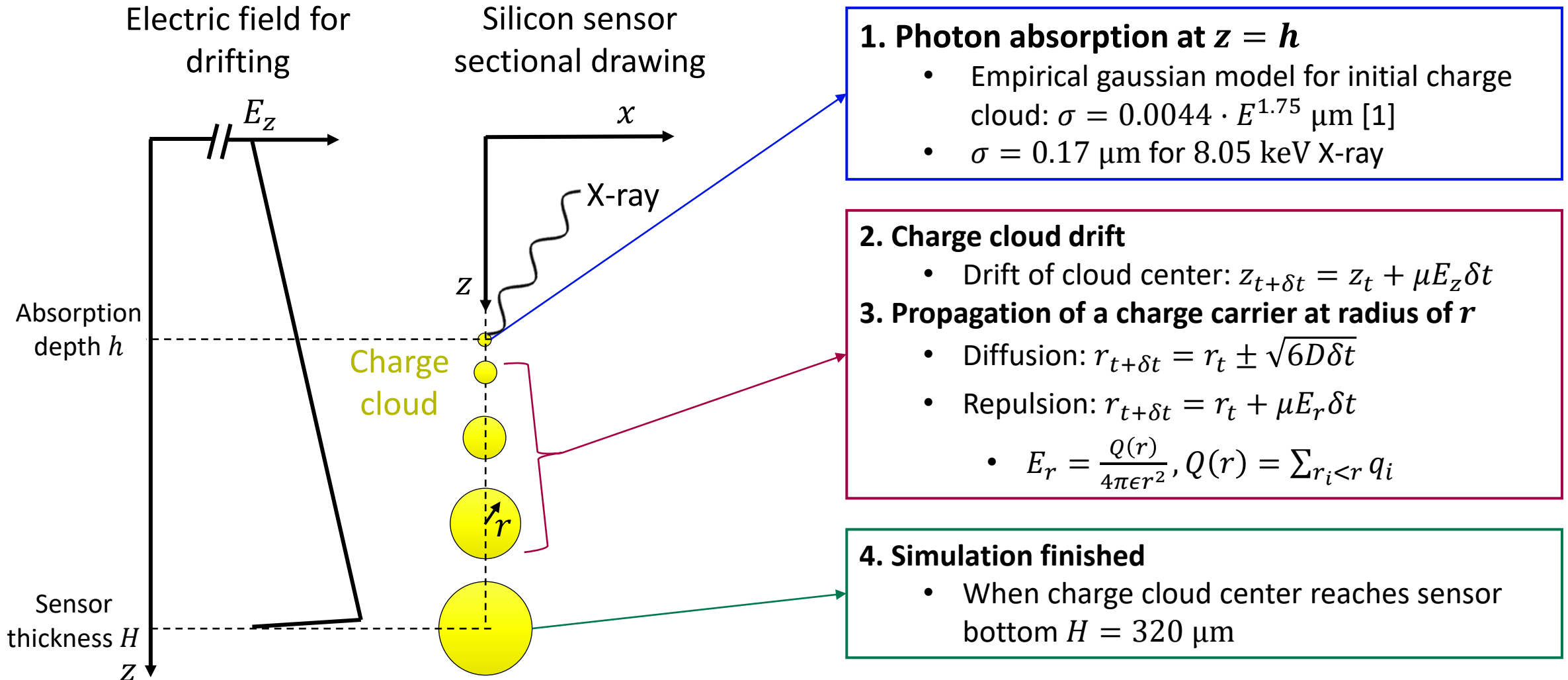
With repulsion simulated, more consistent Monte-Carlo simulation achieved

without repulsion



with repulsion

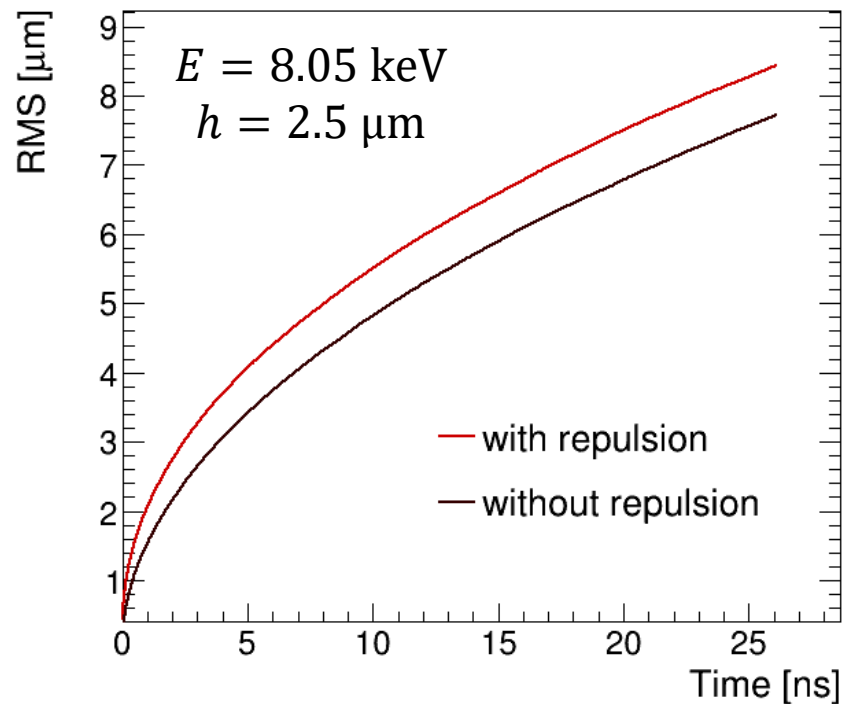




Optimizing Simulation: Intermediate Results

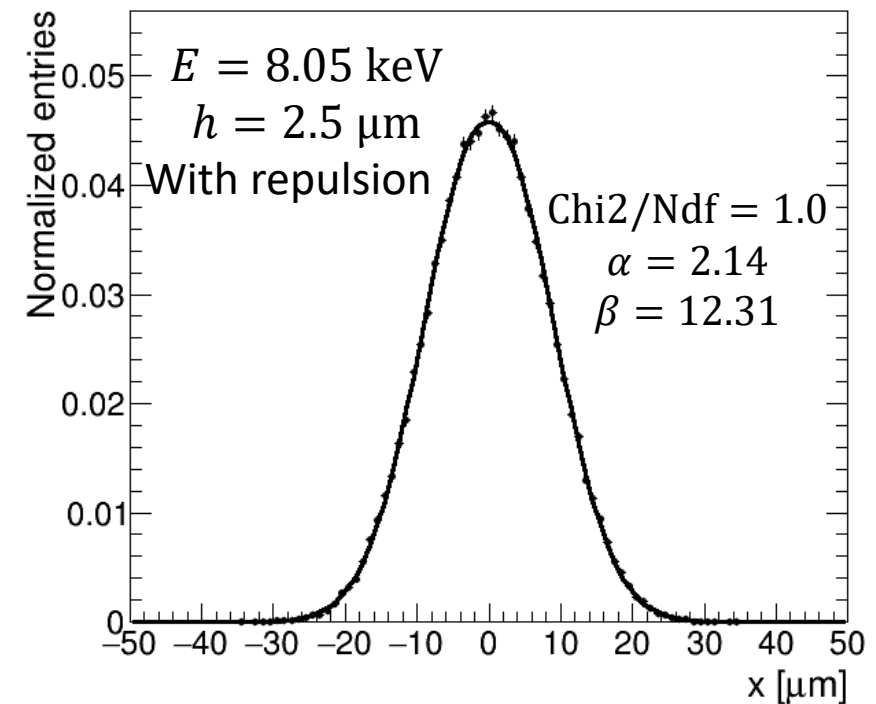
Example: absorption depth $h = 2.5 \mu\text{m}$

- With repulsion, final RMS = $8.46 \mu\text{m}$
- Without repulsion, final RMS = $7.68 \mu\text{m}$



Charge carriers follow the generalized gaussian distribution (GGD)

$$p(x) \sim \frac{\beta}{2\alpha\Gamma(\frac{1}{\beta})} \text{Exp}(-|x|/\alpha)^\beta$$



Validation: Forming 3x3-pixel Cluster

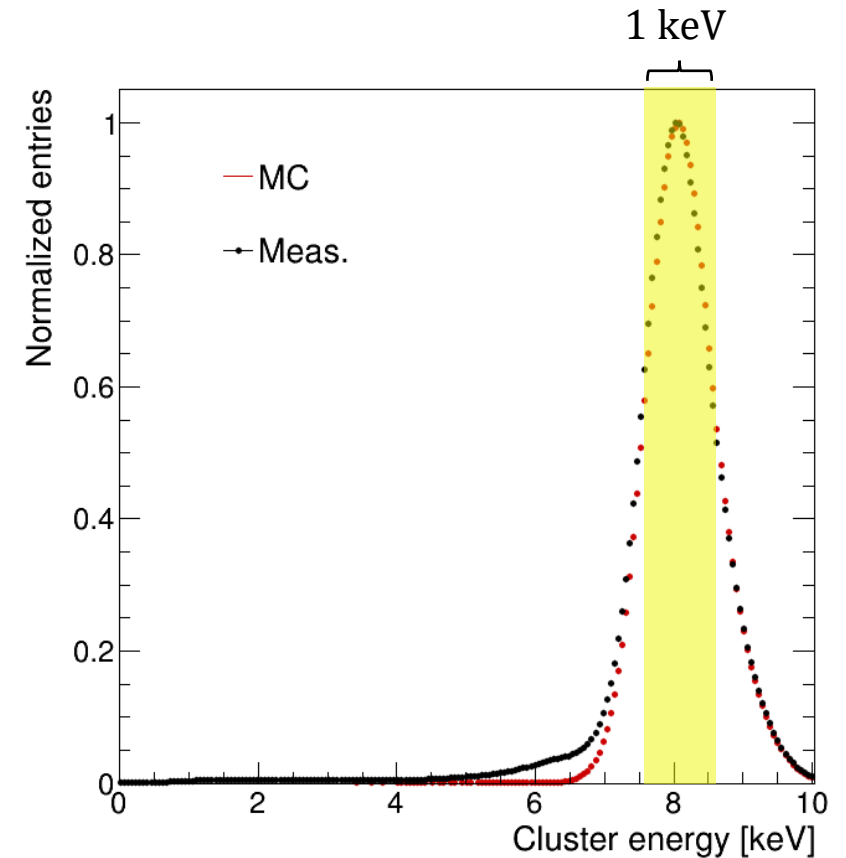
For simulation

1. Simulation conducted at different h every 5 μm
2. X-ray absorption depth h sampled from $\text{Exp}(-\frac{h}{\lambda})$
3. Charge carriers x, y sampled from $\text{GGD}(\alpha, \beta)$
4. Add noise (~ 0.13 keV) and form a 3x3-pixel cluster

For measurement

- Pedestal subtracted
- Pixel-wise gain calibration applied
- Cluster finding

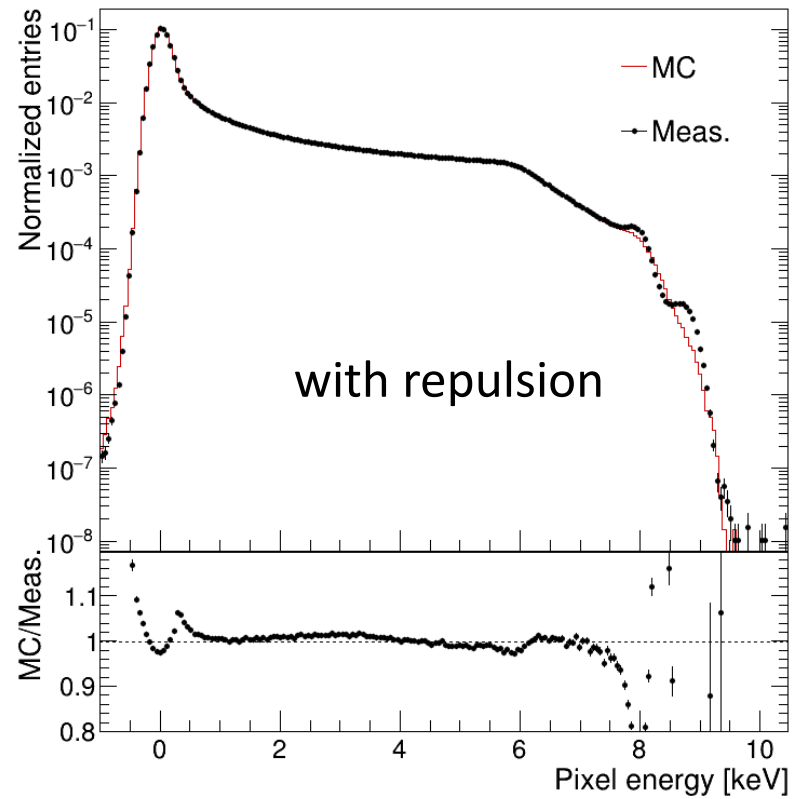
Cluster energy window: $(E_{\text{k}\alpha} - 0.5 \text{ keV}, E_{\text{k}\alpha} + 0.5 \text{ keV})$



Validation: Pixel Energy Spectrum

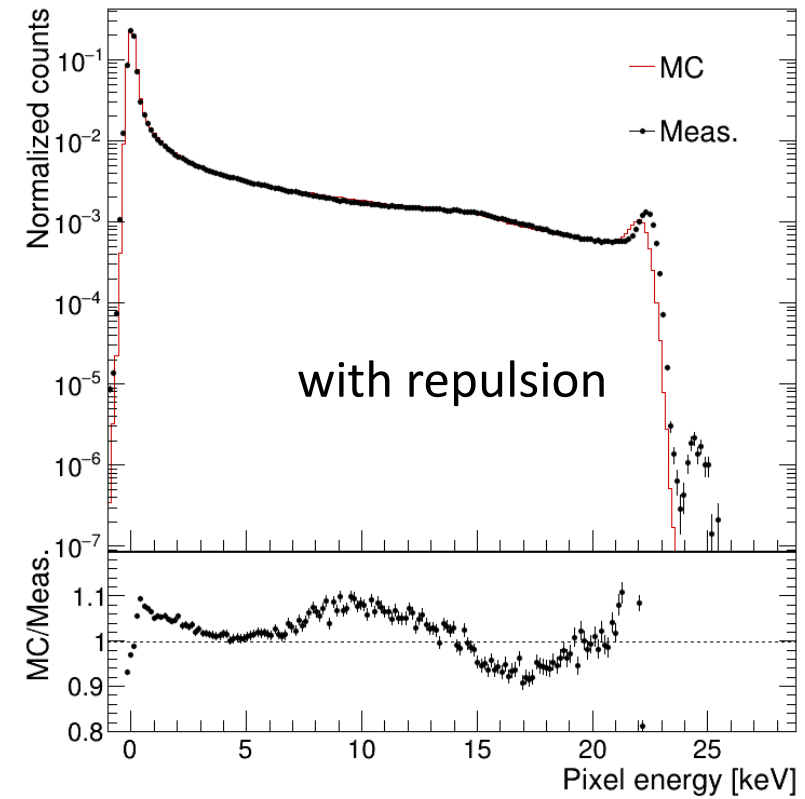
Cu $E_{k\alpha} = 8.05$ keV

Cu $E_{k\beta} = 8.91$ keV



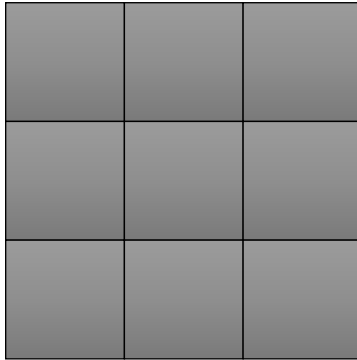
Ag $E_{k\alpha} = 22.16$ keV

Ag $E_{k\beta} = 24.94$ keV



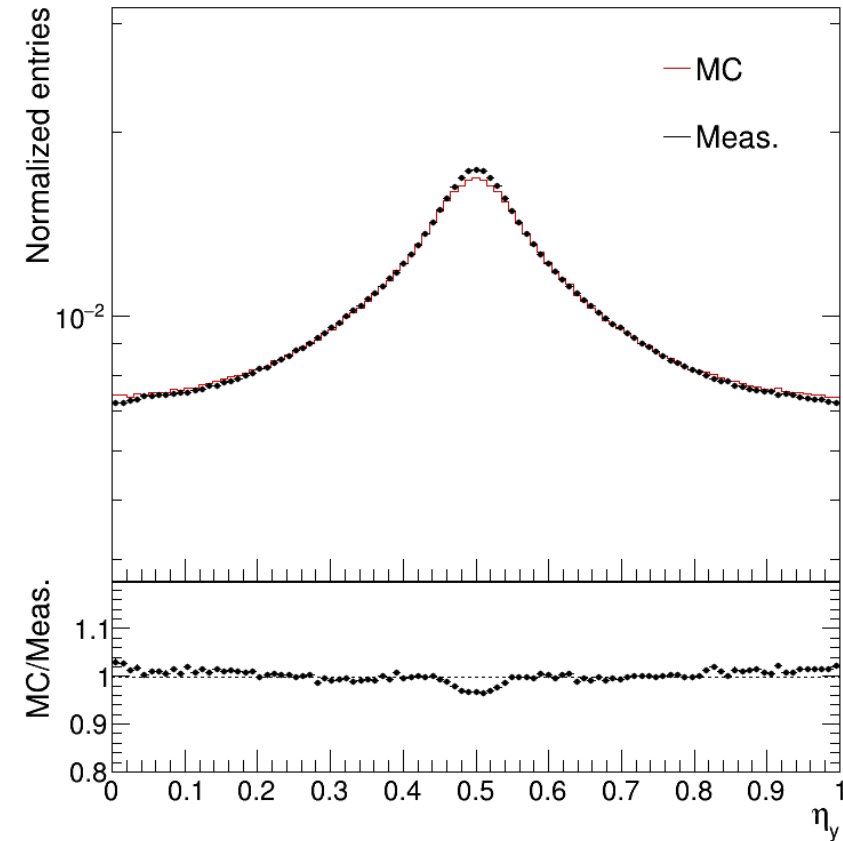
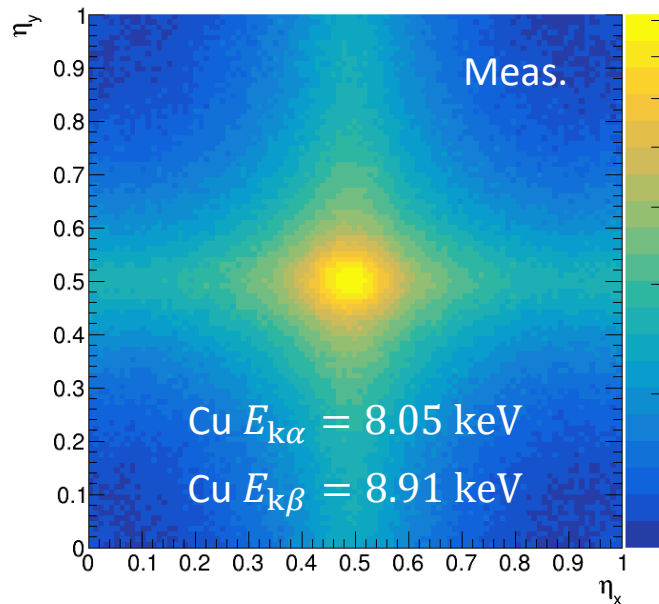
Validation: Charge Weighted Center η_x, η_y

3x3-pixel
cluster



$$\eta_x = \frac{\sum_i Q_i \cdot x_i}{\sum_i Q_i} [1]$$

$$\eta_y = \frac{\sum_i Q_i \cdot y_i}{\sum_i Q_i}$$



[1] E. Belau, et al. (1983). *Nucl. Instrum. Methods Phys. Res.* **214**, 253–260.

Source of remaining mismatch

- Spherical symmetry assumption for charge cloud
 - Gradient of E_z inside charge cloud ignored
 - Asymmetry ignored when charge cloud approaching sensor bottom
- Uncertainty in measurements and modeling
 - Mobility μ , noise modeling
 - Gain uncertainty and non-linearity
 - Pixel crosstalk

To implement for electron simulation

- Parameterization of α, β as functions of absorption depth and E_{deposit}
- Repulsion between adjacent charge clouds

Charge sharing simulation has been optimized

- Repulsion simulation should be considered for small pixel HPD for X-rays/electrons
- Good agreements obtained between measurements and the proposed simulation

To implement as an Allpix2 module

- Better quality of simulation samples for deep learning
- Help optimize detector design by exploiting charge sharing

Thank You!



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Jianguo, Victoria, Shqipe, Anna, Xiangyu, Roberto, Bernd
Missing: Erik, Aldo, Rebecca, Simon, Davide, Dhanya

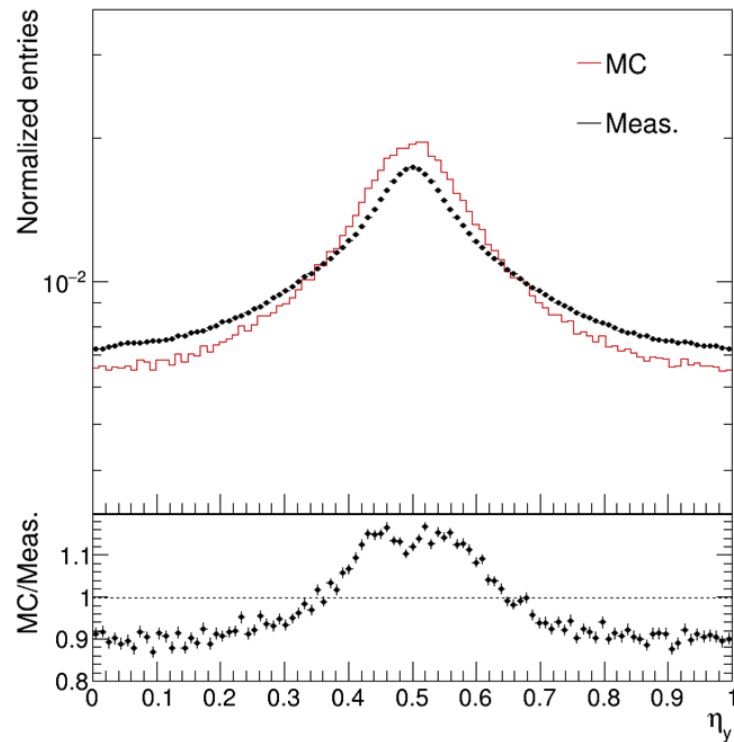
Backup Validation: Charge Weighted Center η_y



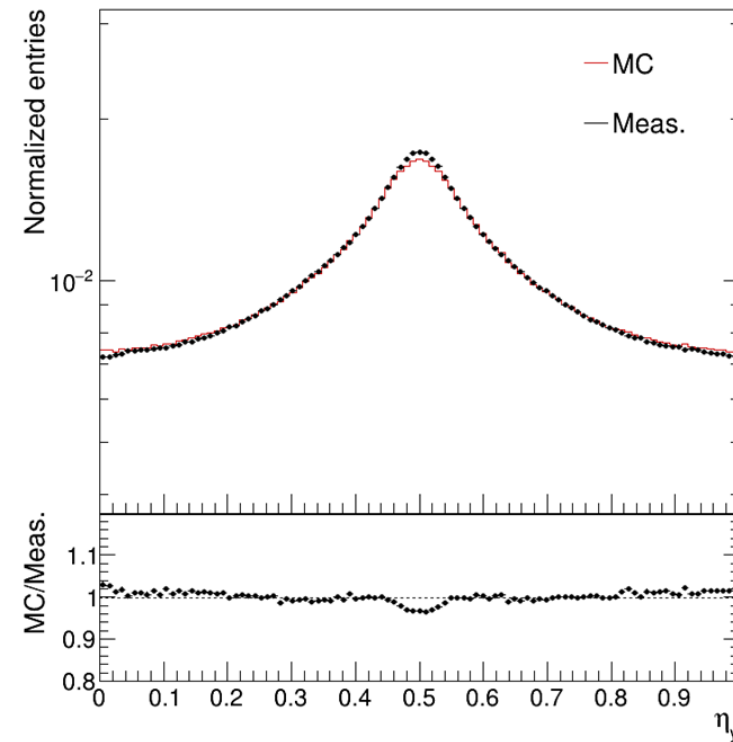
$$\text{Cu } E_{k\alpha} = 8.05 \text{ keV}$$

$$\text{Cu } E_{k\beta} = 8.91 \text{ keV}$$

without repulsion



with repulsion



Backup Optimizing Simulation: Preparations

Coordinates system conventions

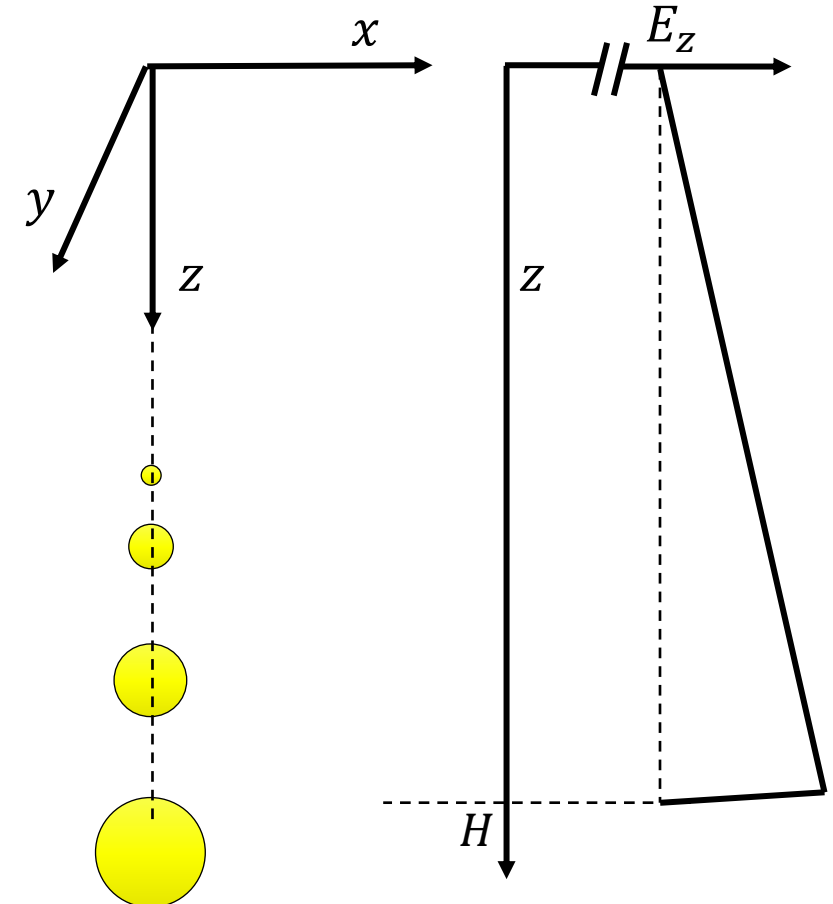
- xy plane is the sensor plane; z axis points backward
- Charge center $(0, 0, z_{\text{center}})$ drifts from $(0, 0, h)$ to $(0, 0, H)$
 - Absorption depth h ; sensor thickness $H = 320 \mu\text{m}$

Drifting electrical field

- $$E_z(z) = \frac{V_{\text{bias}} - V_{\text{dep}}}{H} + \frac{2V_{\text{dep}}}{H} \cdot \frac{z}{H}$$
- $V_{\text{dep}} = 30 \text{ V}, V_{\text{bias}} = 90 \text{ V}$

Initial charge cloud distribution

- $\sigma = 0.0044 \cdot E_{\text{deposit}}^{1.75} \mu\text{m}$,
- Jacoboni-Canali mobility model
- $$\mu(E) = \frac{v_m}{E_c} \frac{1}{(1 + (E/E_c)^\beta)^{1/\beta}}$$



Backup Optimizing Simulation: Recipe of Time Stepping Monte Carlo Simulation

Dynamics of a charge carrier at $(x, y, z + z_{\text{center}})$ while the charge center at $(0, 0, z_{\text{center}})$

- $\mathbf{E}(x, y, z + z_0) = \mathbf{E}_{\text{repulsion}} + \mathbf{E}_{\text{drift}}$
- $\mathbf{E}_{\text{repulsion}}(x, y, z + z_0) = \frac{Q(r)}{4\pi\epsilon r^2} \left(\frac{x}{r} \mathbf{e}_x + \frac{y}{r} \mathbf{e}_y + \frac{z}{r} \mathbf{e}_z \right)$
- $Q(r) = \sum_{i \text{ where } \sqrt{x_i^2 + y_i^2 + z_i^2} < r} q_i$
- Hold under the assumption of spherical symmetry of charge cloud
- $\mathbf{E}_{\text{drift}}(z + z_{\text{center}}) \cong \mathbf{E}_{\text{drift}}(z_{\text{center}}) = \left(\frac{V_{\text{bias}} - V_{\text{dep}}}{H} + \frac{2V_{\text{dep}}}{H} \frac{z_{\text{center}}}{H} \right) \mathbf{e}_z$

$$\text{Mobility } \mu(|\mathbf{E}|) = \frac{v_m}{E_c} \frac{1}{(1 + (|\mathbf{E}|/E_c)^\beta)^{1/\beta}}$$

Coordinates updating for each charge carrier

- Repulsion: $x[t + \delta t] = x[t] + \mu(|\mathbf{E}|) |\mathbf{E}| \frac{x}{\sqrt{x^2 + y^2 + z^2}} \delta t, \delta t := 0.01 \text{ ns}$
- Diffusion: $x[t + \delta t] = x[t] \pm \sqrt{2D\delta t}, D = \mu(|\mathbf{E}|) \frac{kT}{q}$ modelled as random walk